

AM27S191, 'S191A, 'PS191, 'PS191A AM27S291, 'S291A, 'PS291, 'PS291A

16,384-Bit (2048x8) Bipolar PROM

The AM27S191 (2048 words by bits) is a Schottky TTL Programmable Read-Only Memory (PROM).

This device has three-state outputs which are compatible with low-power Schottky bus standards capable of satisfying the requirements of a variety of microprogrammable controls, mapping functions, code conversion, or logic replacement. Easy word-depth expansion is facilitated by both active LOW (G_1) and active HIGH (G_2 and G_3) output enables.

Rochester Electronics Manufactured Components

Rochester branded components are manufactured using either die/wafers purchased from the original suppliers or Rochester wafers recreated from the original IP. All recreations are done with the approval of the OCM.

Parts are tested using original factory test programs or Rochester developed test solutions to guarantee product meets or exceeds the OCM data sheet.

Quality Overview

- ISO-9001
- AS9120 certification
- Qualified Manufacturers List (QML) MIL-PRF-38535
 - Class Q Military
 - Class V Space Level
- Qualified Suppliers List of Distributors (QSLD)
 - Rochester is a critical supplier to DLA and meets all industry and DLA standards.

Rochester Electronics, LLC is committed to supplying products that satisfy customer expectations for quality and are equal to those originally supplied by industry manufacturers.

The original manufacturer's datasheet accompanying this document reflects the performance and specifications of the Rochester manufactured version of this device. Rochester Electronics guarantees the performance of its semiconductor products to the original OEM specifications. 'Typical' values are for reference purposes only. Certain minimum or maximum ratings may be based on product characterization, design, simulation, or sample testing.

Am27S191/S191A/S191SA/PS191/PS191A Am27S291/S291A/S291SA/PS291/PS291A

16,384-Bit (2048x8) Bipolar PROM



DISTINCTIVE CHARACTERISTICS

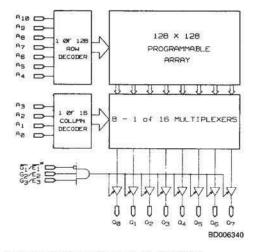
- · Fast access time allows high system speed
- 50% power savings on deselected parts enhances reliability through total system heat reduction (27PS devices)
- Plug in replacement for industry standard product no board changes required
- Platinum-Silicide fuses guarantee high reliability, fast programming and exceptionally high programming yields (typ > 98%)
- Voltage and temperature compensated providing extremely flat AC performance over military range
- Rapid recovery from power-down state provides minimum delay (27PS devices)

GENERAL DESCRIPTION

The Am27S191 (2048 words by 8 bits) is a Schottky TTL Programmable Read-Only Memory (PROM).

This device has three-state outputs which are compatible with low-power Schottky bus standards capable of satisfying the requirements of a variety of microprogrammable controls, mapping functions, code conversion, or logic replacement. Easy word-depth expansion is facilitated by both active LOW ($\overline{G_1}$) and active HIGH (G_2 and G_3) output enables.

This device is also available in 300-mil, lateral center DIP (Am27S291). Additionally, this device is offered in a powerswitched, three-state version (Am27PS191/Am27PS291).



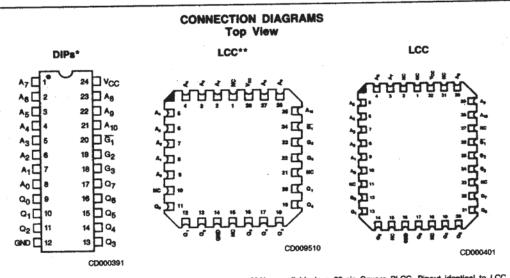
BLOCK DIAGRAM

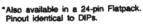
*E nomenclature applies to the power-switched versions only (Am27PSXXX).

PRODUCT SELECTOR GUIDE

Three-State Part Number	Am27S191SA, Am27S291SA		Am27S191A, Am27S291A		Am27S191, Am27S291		Am27PS191A, Am27PS291A		Am27PS191, Am27PS291	
Address Access Time (ns)	25	30	35	50	50	65	50	65	65	75
Operating Range	С	м	С	м	С	M	С	M	С	M

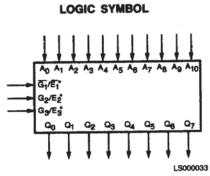
1	Publication (E Bey.	Amendment
	02121	D	/0
	Issue Date:	January	1989





**Also available in a 28-pin Square PLCC. Pinout identical to LCC.

Note: Pin 1 is marked for orientation.



*E nomenclature applies to the power-switched versions only (Am27PSXXX).

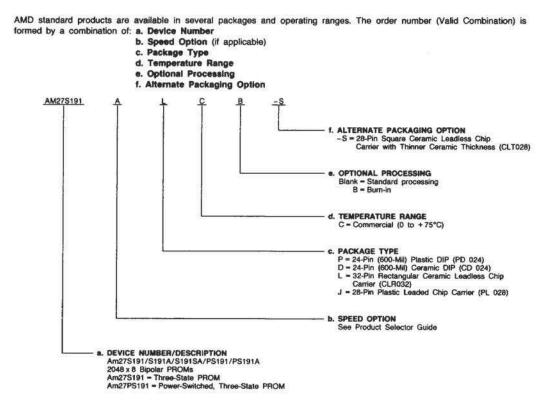
5-187

5

ORDERING INFORMATION

(Am27S191/27PS191)

Standard Products



Valid	Combinations
AM27S191	
AM27S191A	PC, PCB, DC, DCB,
AM27S191SA	LC, LCB, LC-S, LCB-S,
AM27PS191	- JC, JCB
AM27PS191A	1

Valid Combinations

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations, to check on newly released combinations, and to obtain additional data on AMD's standard military grade products.

MILITARY ORDERING INFORMATION

(Am27S191/27PS191)

APL Products

AMD products for Aerospace and Defense applications are available in several packages and operating ranges. APL (Approved Products List) products are fully compliant with MIL-STD-883C requirements. The order number (Valid Combination) for APL products is formed by a combination of: a. Device Number b. Speed Option (if applicable) c. Device Class d. Package Type e. Lead Finish AM275191 SA /B / A //B / A //B /// A + Hot Solder Dip d. PACKAGE TYPE J = 24-Pin (600-Mil) Ceramic DIP (CD 024) K = 24-Pin (600-Mil) Ceramic DIP (CD 024) K = 24-Pin Genamic Clifp (CD 024

Valid	Combinations
AM27S191	
AM27S191A	
AM27S191SA	/BJA, /BKA, /BUA, /B3A
AM27PS191	
AM27PS191A	7

Valid Combinations

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations or to check for newly released valid combinations.

Group A Tests

Group A tests consist of Subgroups 1, 2, 3, 7, 8, 9, 10, 11.

MILITARY BURN-IN

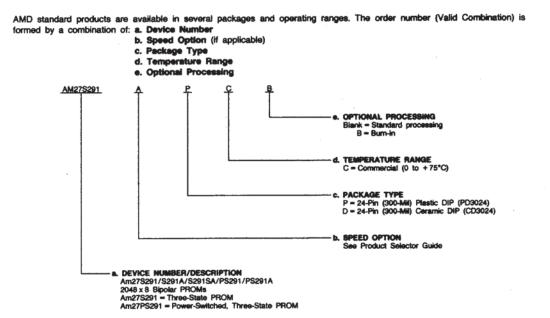
Military burn-in is in accordance with the current revision of MIL-STD-883, Test Method 1015, Conditions A through E. Test conditions are selected at AMD's option.

5

ORDERING INFORMATION

(Am27S291/27PS291)

Standard Products



Valid Combinations				
AM27S291				
AM27S291A				
AM275291SA	PC, PCB, DC, DCB			
AM27PS291	-			
AM27PS291A	1			

Valid Combinations

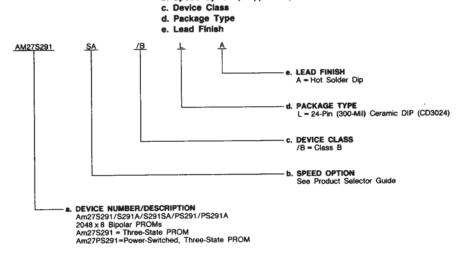
Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations, to check on newly released combinations, and to obtain additional data on AMD's standard military grade products.

MILITARY ORDERING INFORMATION

(Am27S291/27PS291)

APL Products

AMD products for Aerospace and Defense applications are available in several packages and operating ranges. APL (Approved Products List) products are fully compliant with MIL-STD-883C requirements. The order number (Valid Combination) for APL products is formed by a combination of: **a. Device Number b. Speed Option** (if applicable)



Valid C	combinations
AM27S291	
AM27S291A	1
AM27S291SA	/BLA
AM27PS291	7
AM27PS291A	1

Valid Combinations

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations or to check for newly released valid combinations.

Group A Tests

Group A tests consist of Subgroups 1, 2, 3, 7, 8, 9, 10, 11.

MILITARY BURN-IN

Military burn-in is in accordance with the current revision of MIL-STD-883, Test Method 1015, Conditions A through E. Test conditions are selected at AMD's option.

PIN DESCRIPTION

Ao-A10 Address Inputs (Input)

The 11-bit field presented at the address inputs selects one of 2048 memory locations to be read from.

Qo-Q7 Data Output Port (Output)

The outputs whose state represents the data read from the selected memory locations.

G₁, G₂, G₃ Output Enable (Input) Provides direct control of the Q-output buffers. Outputs disabled forces all open-collector outputs to an "OFF" state

FUNCTIONAL DESCRIPTION

Notes on Power Switching

The Am27PS191 and Am27PS291 are power-switched devices. When the chip is selected, important internal currents increase from small idling or standby values to their larger selected values. This transition occurs very rapidly, meaning that access times from the powered-down state are only slightly slower than from the powered-up state. Deselected, ICC is reduced to less than half its full operating amount. Due to this unique feature, there are special considerations which should be followed in order to optimize performance:

and all three-state outputs to a floating or high-impedance state.

Enable =
$$\overline{G_1} \cdot G_2 \cdot G_3$$

Disable = $\overline{G_1} \cdot G_2 \cdot G_3$
= $G_1 + \overline{G_2} + \overline{G_3}$

V_{CC} Device Power Supply Pin The most positive of the logic power supply pins.

GND Device Power Supply Pin The most negative of the logic power supply pins.

- 1. When the Am27PS191 and Am27PS291 are selected, a current surge is placed on the V_{CC} supply due to the powerup feature. In order to minimize the effects of this current transient, it is recommended that a 0.1µf ceramic capacitor be connected from pin 24 to pin 12 at each device. (See Figure 1.)
- 2. Address access time (TAVQV) can be optimized if a chip enable set-up time (TEVAV) of greater than 25ns is observed. Negative set-up times on chip enable (TEVAV < 0) should be avoided. (For typical and worse case characteristics, see Figures 2A and 2B.)

ABSOLUTE MAXIMUM RATINGS

Storage Temperature65 to +150°C
Ambient Temperature with
Power Applied55 to +125°C
Supply Voltage0.5 V to +7.0 V
DC Voltage Applied to Outputs
(Except During Programming)0.5 V to + V _{CC} Max.
DC Voltage Applied to Outputs
During Programming 21 V
Output Current into Outputs During
Programming (Max. Duration of 1 sec) 250 mA
DC Input Voltage0.5 V to +5.5 V
DC Input Current30 mA to +5 mA

Stresses above those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent device failure. Functionality at or above these limits is not implied. Exposure to absolute maximum ratings for extended periods may affect device reliability.

OPERATING RANGES

Commercial (C) Devices

Ambient Temperature (TA) 0 to +75°C Supply Voltage (V_{CC}) +4.75 V to +5.25 V

Military (M) Devices*

Case Temperature (T_C).....-55 to +125°C Supply Voltage (V_{CC})+4.5 V to +5.5 V

Operating ranges define those limits between which the functionality of the device is guaranteed.

*Military product 100% tested at T_C = +25°C, +125°C, and -55°C.

The annumber where

DC CHARACTERISTICS	over operating ranges unless otherwise	specified	(for APL Pr	oducts, Group A,
Subgroups 1, 2, 3 are tested	unless otherwise noted)			

Parameter Symbol	Parameter Description	Test Conditions		Min.	тур.	Max.	Unit
VOH (Note 1)	Output HIGH Voltage	V _{CC} = Min., I _{OH} = -2.0 mA VIN = VIH or VIL		2.4			۷
VOL	Output LOW Voltage	V _{CC} = Min., I _{OL} = 16 mA V _{IN} = V _{IH} or V _{IL}				0.50	۷
VIH	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs (Note 3)		2.0			۷
VIL	Input LOW Level	Guaranteed input logical LOW voltage for all inputs (Note 3)				0.8	۷
հլ	Input LOW Current	V _{CC} = Max., V _{IN} = 0.45 V				-0.250	mA
lin	Input HIGH Current	V _{CC} = Max., V _{IN} = V _{CC}				40	μA
-101	Output Short-Circuit	VCC = Max., VOUT = 0.0 V	COM'L	-20		-90	mA
Isc	Current		MIL	-15		-90	
loc	Power Supply Current	All inputs = GND, V _{CC} = Max.				185	mA
VI	Input Clamp Voltage	Vcc = Min., IIN = -18 mA				-1.2	V
•	Tubar crant course	Vcc = Max.	Vo=Vcc		1000	40	
ICEX	Output Leakage Current	$V_{G1} = 2.4 V$	V _O = 0.4 V			-40	μA
CIN	Input Capacitance	$V_{IN} = 2.0 V @ f = 1 MHz (Note 2)$ $V_{CC} = 5 V, T_A = 25^{\circ}C$			4.0		pF
COUT	Output Capacitance	Vout = 2.0 V @ f = 1 MHz (Note 2) Voc = 5 V, TA = 25°C			8.0		1

5

Notes: 1. Not more than one output should be shorted at a time. Duration of the short-circuit test should not be more than one second.
 2. These parameters are not 100% tested, but are evaluated at initial characterization and at any time the design is modified where capacitance may be affected.
 3. VIL and VIH are input conditions of output tests and are not themselves directly tested. VIL and VIH are absolute voltages with respect to device ground and include all overshoots due to system and/or tester noise. Do not attempt to test these values without suitable equipment.

		Parameter		Am27S Version		Am27PS Version		
Parameter	COM'L			MIL	COM'L	MIL	1	
No.	Symbol	Description	Version	Max.	Max.	Max.	Max.	Unit
		SA	25	30				
1	TAVQV	Address Valid to Output Valid Access		35	50	50	65	ns
		STD	50	65	65	75	1	
	TGVQZ	Delay from Output Enable Valid to A Output Hi-Z STD	SA	18	20			
2	TEVOZ		A	25	30	25	30	ns
			25	30	35	45		
	TGVQV	Delay from Output Eachie Malia to	SA	18	20			
3	TEVQV	Delay from Output Enable Valid to Output Valid	A	25	30	65	75	ns
		STD	25	30	80	90		
4	TAVQV1	Power-Switched Address Valid to Output Valid Access Time (Am27PS Versions	A			65	75	
		only)	STD			80	90	ns

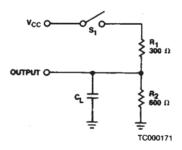
SWITCHING CHARACTERISTICS over operating ranges unless otherwise specified (for APL Products, Group A, Subgroups 9, 10, 11 are tested unless otherwise noted*)

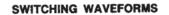
See also Switching Test Circuits.

See also Switching Test Circuits.
Notes: 1. Tests are performed with input transition time of 5 ns or less, timing reference levels of 1.5 V, and input pulse levels of 0 to 3.0 V.
2. TGVQZ is measured at steady state HIGH output voltage -0.5 V and steady state LOW output voltage +0.5 V output levels.
3. TAVQV is tested with 0.1 e50 pF to the 1.5 V level; 51 is open for high impedance to HIGH tests and closed for high impedance to LOW tests. TGVQZ is tested with 0.1 e50 pF. HIGH to high impedance tests are made with 51 open to an output voltage of steady state HGH -0.5 V with 51 open; LOW-to-HIGH impedance tests are made to the steady state LOW +0.5 V level with 51 closed.
*Subtrours 7 and 8 and the test.

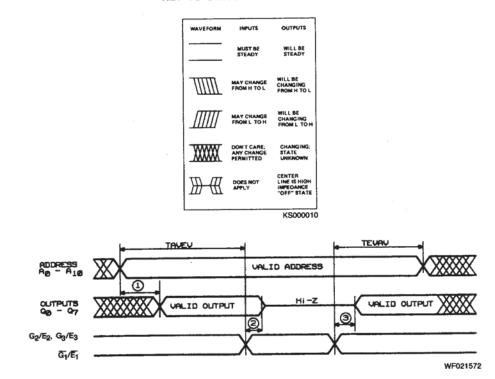
*Subgroups 7 and 8 apply to functional tests.

SWITCHING TEST CIRCUIT





KEY TO SWITCHING WAVEFORMS



5